





GOLDSCOPE[®] SD 600

Advanced high-end ED-XRF Machine for Gold, Silver and other precious metal analysis



All-in-One solutions for precious metal analysis and coating thickness measurement

Precious Metal Analysis | Multi-Layer Thickness Measurement | Solution Analysis | Alloy composition | Silver Testing





Precious Metal Analysis

Features

- Modern Silicon Drift Detector (SDD) for high accuracy and a good detection sensitivity.
- High-resolution colour video camera for precise determination of the measurement spot.
- Bench-top unit with front door opening.
- Available in two option
 SDD detector with 20 mm² (160 eV)
 SDD detector with 50 mm² (140 eV)
- Scissor table (Lab-Jack) for Z-axis movement
- Micro-focus tungsten tube with beryllium window
- Elemental Range: Aluminium Al (13) to Uranium U (92)
- Powerful and user-friendly WinFTM[®] software.
- Option to remove scissor table to accommodate bigger sample







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High resolution Silicon Drift Detector with large aperture (Ø2 mm, 79 mils) enables GOLDSCOPE SD 600 to achieve highest accuracy with a short measurement time.

Application

- Jewelry, precious metals and dental alloys
- Precious Metal Analysis eg. Gold, Silver and Platinum group elements
- Measuring coating thickness on sterling silver, rhodium finishes or gold alloys
- Determination of complex multi layer-coating system
- Platinum, Yellow , white gold , Rhodium and silver
- Alloy Composition
- Solution Analysis
- Solutions for refineries, tunch assay offices and hallmarking
- Detection of PGM Group elements such as Iridium, Ruthenium, Osmium, Rhenium enabling an accurate precious metal analysis results.
- Materials analysis of coatings and alloys (also thin coatings and low concentrations)



The modern Silicon Drift Detector (SDD) achieves a high accuracy and a good detection sensitivity. This results in high resolution for light elements. Outstanding accuracy and long-term stability are characteristics of all FISCHERSCOPE X-RAY systems. The necessity of recalibration is considerably reduced, saving time and effort. The fundamental parameter method by FISCHER allows for the analysis of solid and liquid specimens as well as coating systems without calibration.

Design

The new FISCHER XRF - GOLDSCOPE[®] SD 600 is designed as a user-friendly bench-top instrument. It is equipped with a manual operated scissor table (Lab-Jack) for Z-axis movement to measure complex samples. Sample placement area is designed in such a way that samples of any shape right from small connectors to complex automotive parts can be easily accommodated.

A laser pointer serves as a positioning aid and supports the quick alignment of the sample to be measured. A high-resolution colour video camera simplifies the precise determination of the measurement spot.

The entire operation and evaluation of measurements as well as the clear presentation of measurement data is performed on a PC, using the powerful and user-friendly WinFTM® software.



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General Specification

Intended Use	Energy Dispersive X-Ray Fluorescence measuring instrument (EDXRF) for precious metal, alloys analysis in hallmarking, testing, tunch assaying offices, refineries, retail stores & gold manufacturing.	
Design	Bench-top unit with front door opening and manually operated scissor table for Z-axis movement Video camera and laser pointer (class 1) for orienting the sample	
Measuring Direction	From top to bottom	
X-ray tube	Micro-focus tube with beryllium window	
High voltage	High voltage three steps: 10 kV, 30 kV, 50 kV	
Apertures (Collimators)	4x changeable: 0.2 mm, 0.6 mm, 1.0 mm, 2.0 mm, others on request	
Primary filter	3x changeable (Standard configuration: Nickel, Aluminum, no filter)	
Sample Stage	Manually adjustable scissor table (Lab-Jack)	
Measurement spot	Depending on the measuring distance and on the aperture, the actual measurement is shown in video image.	

Environmental Conditions

Operating temperature	10 °C – 40 °C		
Storage / Transport temperature	0 °C – 50 °C		
Relative humidity	≤ 95 %		
X-Ray Detector	Standard (20 mm²)	Optional (50 mm²)	
X-ray detector Resolution (fwhm for Mn-K)	Silicon Drift detector with peltier cooling ≤ 160 eV	Silicon Drift detector with peltier cooling ≤140 eV	
Element range	Aluminum Al (13) – Uranium U (92)		
Measuring distance	0 80 mm		
	Distance compensation with patented DCM method for simplified measurements at varying distances. For particular applications or for higher demands on accuracy an additional calibration might be necessary.		
Sample Alignment			
Video microscope	High-resolution CCD colour camera for optical monitoring of the measurement location along the primary beam axis, manual focusing and crosshairs with a calibrated scale (ruler) and spot -indicator, adjustable LED illumination, laser pointer (class 1) to support accurate sample placement.		
Zoom factor	Digital 1x, 2x, 3x, 4x		
Electrical Data			
Power source Power consumption Protection class	AC 115 V or AC 230 V 50 / 60 Hz max. 120 W, without evaluation PC IP 40		
Target Dimensions			
External dimensions Sample Placement Area Scissor Table Weight approx	500 x 515 x 525 mm (Width x depth x height [mm]) 345 x 300 x 145 mm (Width x depth x height [mm]) 150 x 120x 140 mm (Width x depth x height [mm]) 75 Kg		
Evaluation Unit			
Computer Software Standard	Windows based PC Fischer WinFTM®		
Standards			
X-Ray standards	DIN ISO 3497 and ASTM B 568		
Order			

GOLDSCOPE[®] SD 600 Standard (20mm²) Option SDD (50mm²) Part No.

IN605-687

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